

Notice of References Cited	Application/Control No. 10/754,565		Applicant(s)/Patent Under Reexamination MOULI, CHANDRA	
	Examiner Steven Loke		Art Unit 2811	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,046,487	04-2000	Benedict et al.	257/510
	B	US-6,570,222	05-2003	Nozaki et al.	257/347
	C	US-2002/0117731	08-2002	Kim et al.	257/510
	D	US-2005/0042793	02-2005	Mouli et al.	438/057
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Charge properties of aluminum oxide layers synthesized by molecular layering" by Sazonov et al., Technical Physics Letters, Volume 24, No. 7, July 1998, pages 525-526.
	V	"Breakdown and generation of interface states in oxynitride thin films on silicon" by Novkovski, Semiconductor Science and Technology 17 No. 2, 10 January 2002, pages 93-96.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.